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Hihara, H.; Sato, M.; Fukasawa, K.; Sase, H.; Osawa, Y.; Ito, N.;  
TENCON '02. Proceedings. 2002 IEEE Region 10 Conference on Computers, Communications, Control and Power Engineering , Volume: 2 , 28-31 Oct. 20  
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Kawamata, S.; Ito, N.; Katahara, S.; Aoki, M.;  
Intelligent Vehicle Symposium, 2002. IEEE , Volume: 1 , 17-21 June 2002  
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Kuwata, Y.; Noda, I.; Ohta, M.; Ito, N.; Shinhoda, K.; Matsuno, F.;  
SICE 2002. Proceedings of the 41st SICE Annual Conference , Volume: 2 , 5-  
2002  
Pages:860 - 864 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(369KB\)\]](#) IEEE CNF**19 Ultralow k nanoporous silica by oxidation of silicon nanoparticles**

Nozaki, S.; Ono, H.; Uchida, K.; Morisaki, H.; Ito, N.; Yoshimaru, M.;  
Interconnect Technology Conference, 2002. Proceedings of the IEEE 2002  
International , 3-5 June 2002  
Pages:69 - 71

[\[Abstract\]](#) [\[PDF Full-Text \(298KB\)\]](#) IEEE CNF**20 Location detection system by an on-board slit camera imaging road surface marks and its application**

Kawamata, S.; Ito, N.; Katahara, S.; Aoki, M.;  
Intelligent Transportation Systems, 2002. Proceedings. The IEEE 5th Internat

Conference on , 2002  
Pages:78 - 83

[\[Abstract\]](#) [\[PDF Full-Text \(585KB\)\]](#) IEEE CNF

---

**21 Two-step copper electroplating technique using seed enhancement with alkali-metal-free copper pyrophosphate bath**

*Hosoi, N.; Kimizuka, R.; Nagai, M.; Okuyama, S.; Kobayashi, T.; Ito, N.; Arita, Miyamoto, H.;*

Interconnect Technology Conference, 2001. Proceedings of the IEEE 2001 International , 4-6 June 2001  
Pages:277 - 279

[\[Abstract\]](#) [\[PDF Full-Text \(252KB\)\]](#) IEEE CNF

---

**22 Development of a two-step electroplating process with a long-term stability for applying to Cu metallization of 0.1  $\mu\text{m}$  generation logic UI**

*Arita, K.; Ito, N.; Hosoi, N.; Miyamoto, H.;*

Semiconductor Manufacturing Symposium, 2001 IEEE International , 8-10 Oct 2001  
Pages:155 - 158

[\[Abstract\]](#) [\[PDF Full-Text \(447KB\)\]](#) IEEE CNF

---

**23 Simulation and dispatching systems for production fab management**

*Ishii, Y.; Ito, N.;*

Semiconductor Manufacturing Symposium, 2001 IEEE International , 8-10 Oct 2001  
Pages:429 - 432

[\[Abstract\]](#) [\[PDF Full-Text \(233KB\)\]](#) IEEE CNF

---

**24 Micro-structuring of  $\text{SiO}_2$  thin film on Si by a femto-second laser pulse**

*Kawamura, K.; Ito, N.; Hirano, M.; Hosono, H.;*

Microprocesses and Nanotechnology Conference, 2001 International , 31 Oct. Nov. 2001  
Pages:174 - 175

[\[Abstract\]](#) [\[PDF Full-Text \(276KB\)\]](#) IEEE CNF

---

**25 Relation between the ac loss current method and the PEA method for water-treed length**

*Ito, N.; Ozaki, T.; Sengoku, I.; Kawai, J.; Nakamura, S.;*

Electrical Insulating Materials, 2001. (ISEIM 2001). Proceedings of 2001 International Symposium on , 19-22 Nov. 2001  
Pages:524 - 527

[\[Abstract\]](#) [\[PDF Full-Text \(267KB\)\]](#) IEEE CNF

---

**26 Changes of capacitance and dielectric dissipation factor of water-treated XLPE with voltage**

*Ozaki, T.; Ito, N.; Sengoku, I.; Kawai, J.; Nakamura, S.;*

Electrical Insulating Materials, 2001. (ISEIM 2001). Proceedings of 2001

International Symposium on , 19-22 Nov. 2001  
Pages:459 - 462

[\[Abstract\]](#) [\[PDF Full-Text \(265KB\)\]](#) IEEE CNF

---

**27 Large area deposition of hydrogenated amorphous silicon by VHF-PECVD using novel electrodes**

*Ito, N.; Kondo, M.; Matsuda, A.;*

Photovoltaic Specialists Conference, 2000. Conference Record of the Twenty-1  
IEEE , 15-22 Sept. 2000

Pages:900 - 903

[\[Abstract\]](#) [\[PDF Full-Text \(228KB\)\]](#) IEEE CNF

---

**28 A high reliability copper dual-damascene interconnection with direct contact via structure**

*Ueno, K.; Suzuki, M.; Matsumoto, A.; Motoyama, K.; Tonegawa, T.; Ito, N.; /  
K.; Tsuchiya, Y.; Wake, T.; Kubo, A.; Sugai, K.; Oda, N.; Miyamoto, H.; Saito*  
Electron Devices Meeting, 2000. IEDM Technical Digest. International , 10-13  
2000

Pages:265 - 268

[\[Abstract\]](#) [\[PDF Full-Text \(376KB\)\]](#) IEEE CNF

---

**29 Control of behavior of particles flaked off an anode in plasma etch-equipment by bias electrode**

*Moriya, T.; Ito, N.; Uesugi, F.; Hayashi, Y.; Okamura, K.;*

Semiconductor Manufacturing, 2000. Proceedings of ISSM 2000. The Ninth  
International Symposium on , 26-28 Sept. 2000

Pages:367 - 370

[\[Abstract\]](#) [\[PDF Full-Text \(454KB\)\]](#) IEEE CNF

---

**30 Exploitation/exploration learning for MDP environment**

*Iwata, K.; Ito, N.; Yarnauchi, K.; Ishii, N.;*

Industrial Electronics Society, 2000. IECON 2000. 26th Annual Conference of  
IEEE , Volume: 1 , 22-28 Oct. 2000

Pages:149 - 154 vol.1

[\[Abstract\]](#) [\[PDF Full-Text \(358KB\)\]](#) IEEE CNF

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